

**Search Notes**

Application/Control No.

09/996,127

Examiner

Jacques Veillard

Applicant(s)/Patent under  
Reexamination

CHAN ET AL.

Art Unit

2165

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	7/5/2005	J.V
707	2-10	7/5/2005	J.V
707	100-104.1	7/5/2005	J.V
707	200, 203	7/5/2005	J.V
706	45, 922	7/6/2005	J.V
709	203, 229	7/6/2005	J.V
717	116,140	7/6/2005	J.V

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
707	5,6,10	7/5/2005	J.V
707	102,104.1	7/5/2005	J.V
706	45, 922	7/6/2005	J.V
709/203, 229		7/6/2005	J.V

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated East Database search.	7/5/2005	J.V
ACM and IEEE (NPL) Electronic database search.	7/6/2005	J.V
Consulted with Jeffrey G. SPE AU 2165.	7/6/2005	J.V
consulted with Swann T. TQAS TC 2100. Claims 22-28 are not statutory as a "Sign per se"	7/11/2005	J.V